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## Confirmation Letter

To,

Neena Srivastava

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**Subject:** Publication of paper at International Journal of Emerging Technologies and Innovative Research .

Dear Author,

With Greetings we are informing you that your paper has been successfully published in the International Journal of Emerging Technologies and Innovative Research (ISSN: 2349-5162). Following are the details regarding the published paper.

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Thank you very much for publishing your article in JETIR. We would appreciate if you continue your support and keep sharing your knowledge by writing for our journal JETIR.

Editor In Chief

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